

N-Channel Super Gate Trench Power MOSFET

RCS023N10BQ

FEATURES

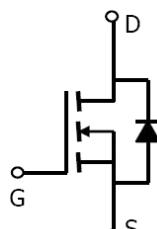
- Super TrenchFET® Power MOSFET
- 100% avalanche tested
- Improved dv/dt capability

APPLICATIONS

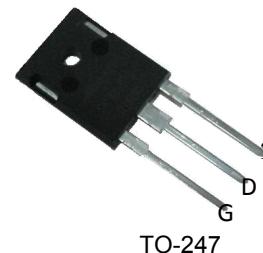
- Primary Side Switch
- Other Applications
- Uninterruptible power supply

Parameter Summary

VDS:100V ID (at VGS=10V) :180A Rds(on) (at VGS=10V):1.8mΩ(Typ.)



Symbol



Device Ordering Marking Packing Information

Ordering Number	Package	Marking	Packing
RCS023N10BQ	TO-247	RCS023N10BQ	Tube

Absolute Maximum Ratings $T_C = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Value	Unit
		TO-247	
Drain-Source Voltage ($V_{GS} = 0\text{V}$)	V_{DSS}	100	V
Continuous Drain Current Package Limited		180	A
Continuous Drain Current	I_D Silicon Limited	305	A
Continuous Drain Current @ $T_C = 100^\circ\text{C}$		190	A
Pulsed Drain Current (note1)	I_{DM}	720	A
Gate-Source Voltage	V_{GSS}	± 20	V
Single Pulse Avalanche Energy (note2)	E_{AS}	900	mJ
Power Dissipation ($T_C = 25^\circ\text{C}$)	P_D	416	W
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55~+150	$^\circ\text{C}$

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Resistance

Parameter	Symbol	Value	Unit
		TO-247	
Thermal Resistance, Junction-to-Case	R_{thJC}	0.3	
Thermal Resistance, Junction-to-Ambient	R_{thJA}	62.5	$^\circ\text{C/W}$

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Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
Static						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	100	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 100, V_{\text{GS}} = 0\text{V}, T_J = 25^\circ\text{C}$	--	--	1.0	μA
Gate-Source Leakage	I_{GSS}	$V_{\text{GS}} = \pm 20\text{V}$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{\text{GS}(\text{th})}$	$I_{\text{DS}} = 250\mu\text{A}$	2.0	--	4.0	V
Drain-Source On-Resistance (Note3)	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 50\text{A}$	--	1.8	2.3	$\text{m}\Omega$
Dynamic						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 50\text{V}, f = 1.0\text{MHz}$	--	11000	--	pF
Output Capacitance	C_{oss}		--	1700	--	
Reverse Transfer Capacitance	C_{rss}		--	350	--	
Total Gate Charge	Q_g	$V_{\text{DD}} = 50\text{V}, I_D = 100\text{A}, V_{\text{GS}} = 10\text{V}$	--	224	--	nC
Gate-Source Charge	Q_{gs}		--	80	--	
Gate-Drain Charge	Q_{gd}		--	38	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 50\text{V}, I_D = 100\text{A}, V_{\text{GS}} = 10\text{V}$ $R_G = 1.6 \Omega$	--	35	--	ns
Turn-on Rise Time	t_r		--	25	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	75	--	
Turn-off Fall Time	t_f		--	30	--	
Drain-Source Body Diode Characteristics						
Continuous Body Diode Current	I_S	$T_C = 25^\circ\text{C}$	--	--	180	A
Pulsed Diode Forward Current	I_{SM}		--	--	720	
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}, I_{\text{SD}} = 50\text{A}, V_{\text{GS}} = 0\text{V}$	--	0.9	1.2	V
Reverse Recovery Time	t_{rr}	$V_{\text{GS}} = 0\text{V}, I_S = 100\text{A}, dI_F/dt = 500\text{A}/\mu\text{s}$	--	100	--	ns
Reverse Recovery Charge	Q_{rr}		--	280	--	nC

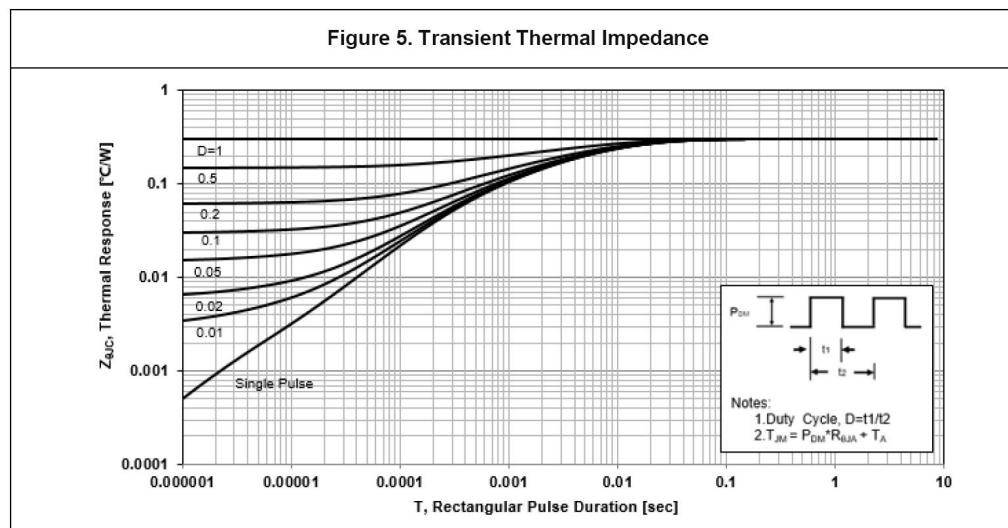
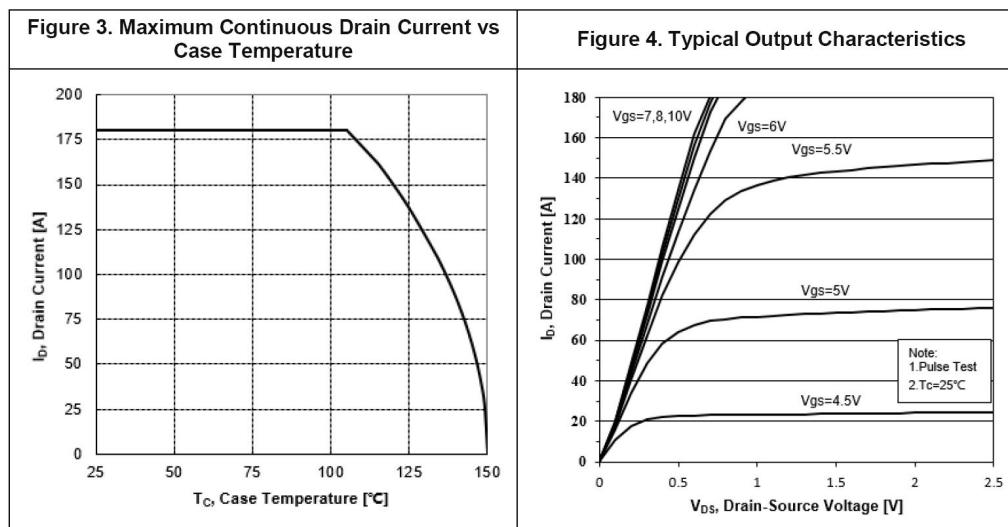
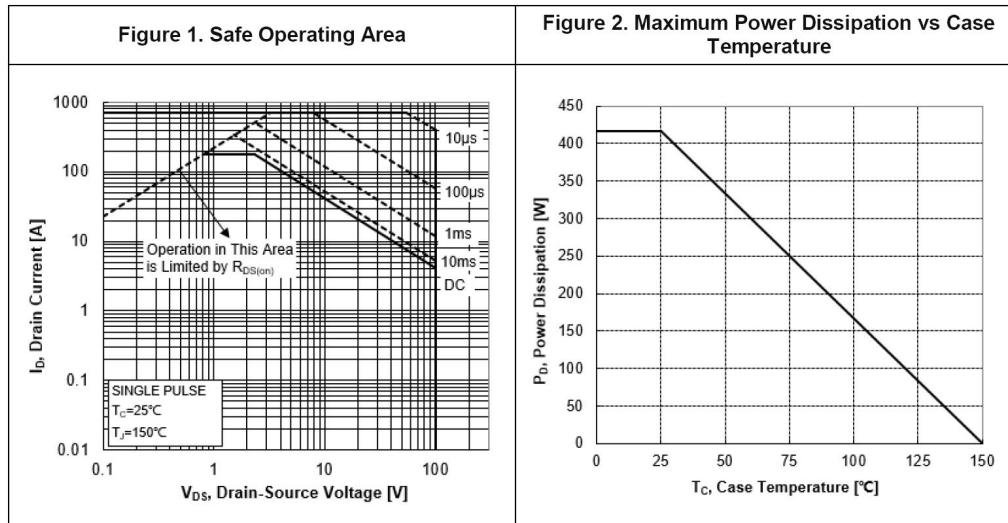
Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. $V_{\text{DD}} = 50\text{V}, R_G = 25 \Omega$, Starting $T_J = 25^\circ\text{C}$
3. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 1\%$

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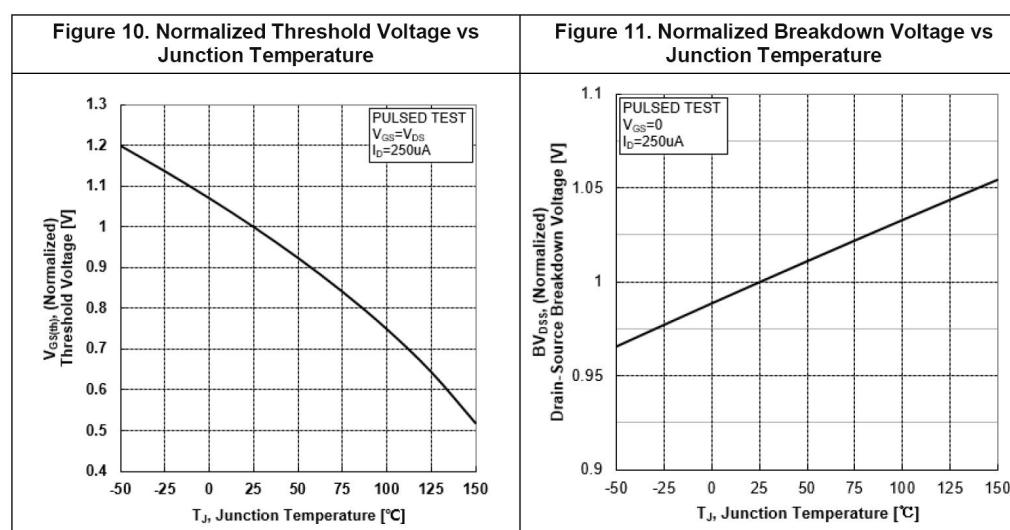
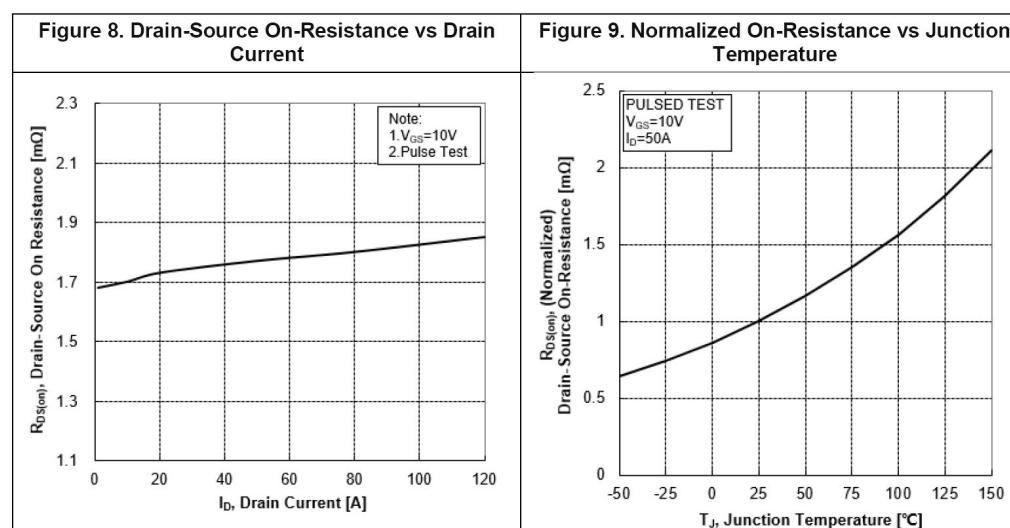
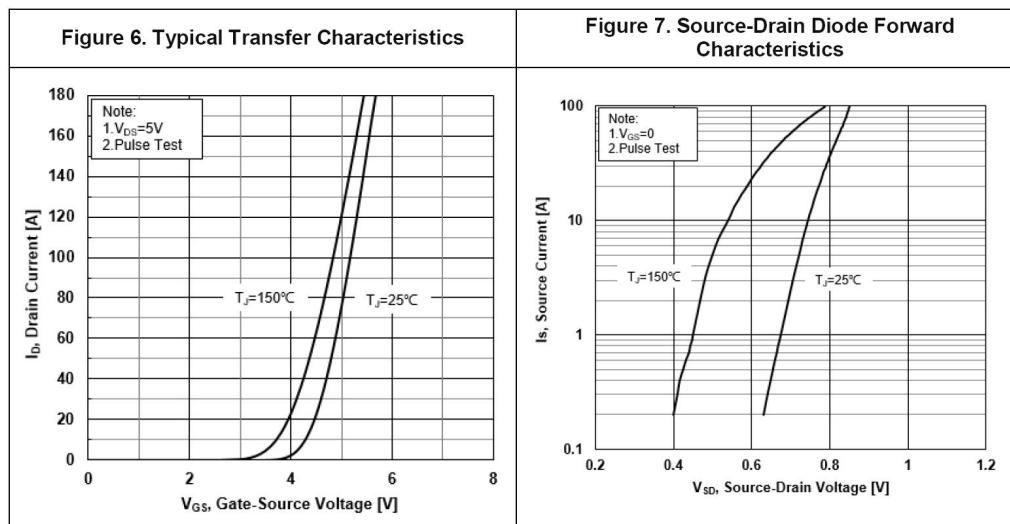
Typical Characteristics $T_J = 25^\circ\text{C}$, unless otherwise noted



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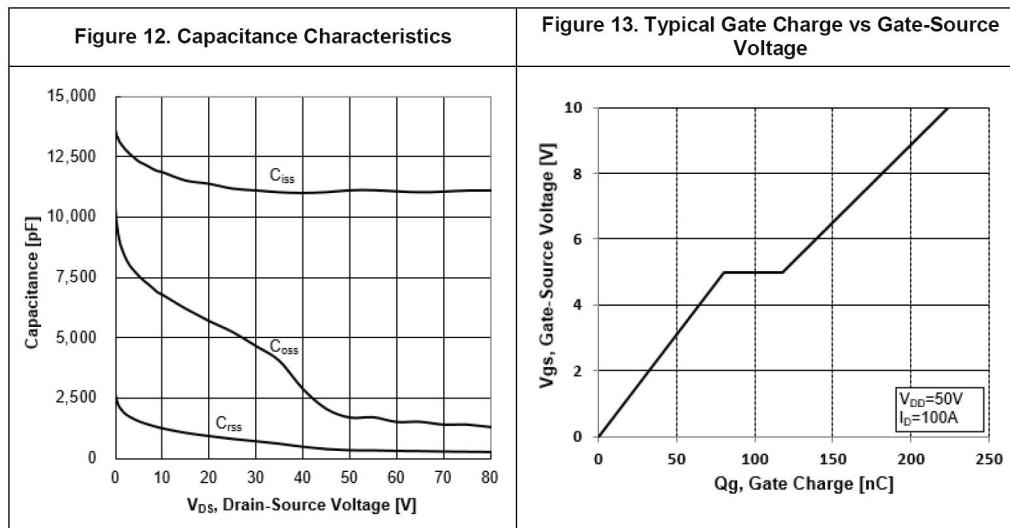
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TEST CIRCUITS AND WAVEFORMS

Figure A: Gate Charge Test Circuit and Waveform

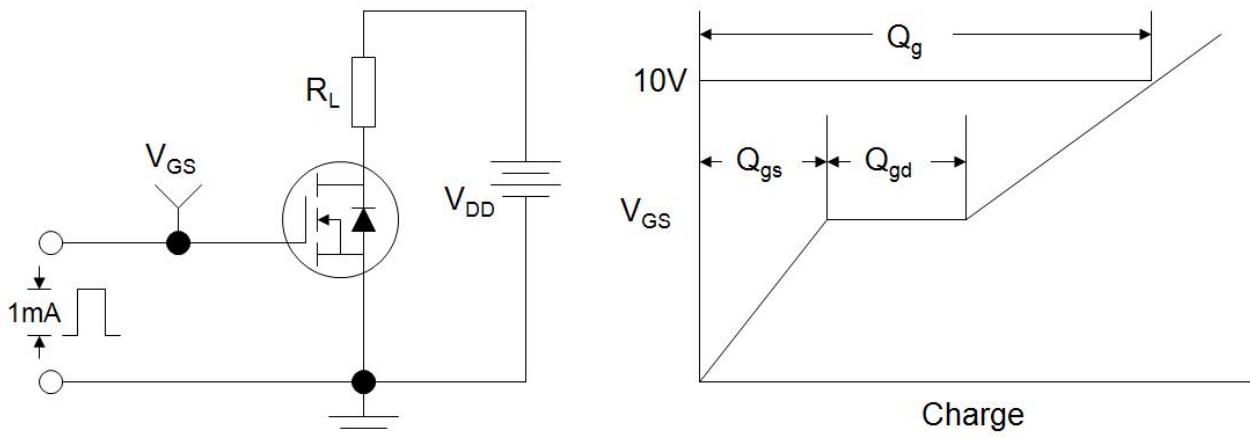


Figure B: Resistive Switching Test Circuit and Waveform

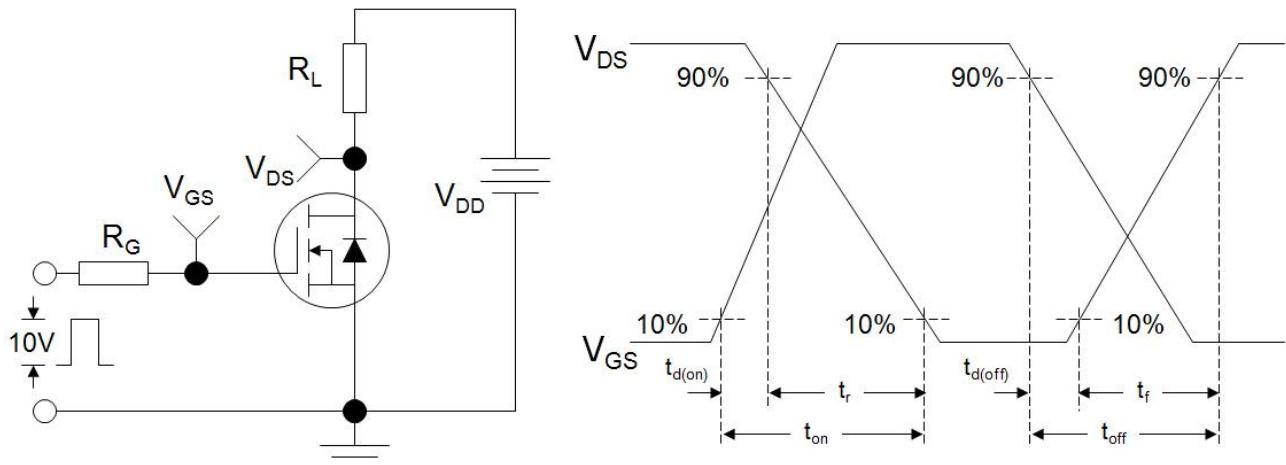


Figure C: Unclamped Inductive Switching Test Circuit and Waveform

